

# Electroformed Integral Shells for the Con-X HXT: May 2003 Update



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# Presentation Topics

- Review of integral shell mirror and its advantages
- Point out error in TRIP report's description of integral shell mirror
- Reason for coating inner shells with Iridium rather than W/Si
- Installation of Jensen-Christensen collimator in deposition chamber
- Impending stress tests
- Report progress in construction of prototype mirror for X-ray testing

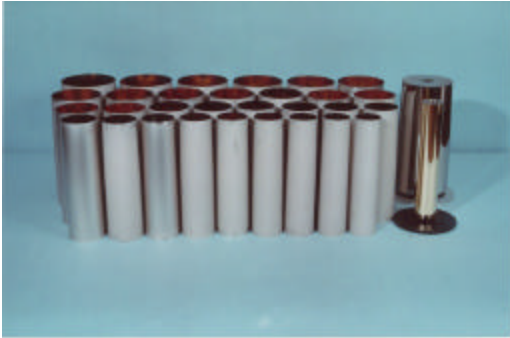
# Electroformed Integral Shells for the Con-X HXT

## Advantages compared to segmented mirrors

- Expect better angular resolution from stiff closed shells as shown by experience: **JET-X/SWIFT 17" HPD**, **XMM-Newton 15" HPD** and recent measurement of thin replica from JET-X (SWIFT) mandrel
- Replication well adapted to making 12 or more identical copies
- Simpler integration of reflectors into a telescope, 90 to 112 shells per telescope, total of 1000 to 1340 shells for all four Con-X S/C

**Note: Error in TRIP report, which states there are 5400 shells**

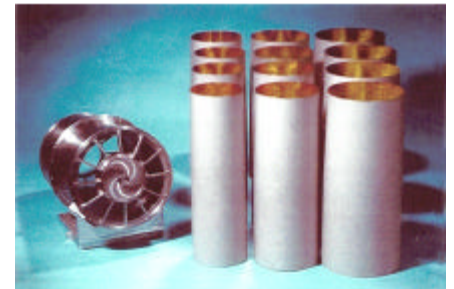
# Heritage of Electroformed X-ray Telescopes



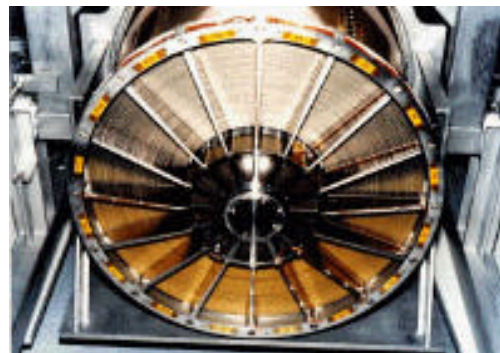
**Beppo/SAX**



**SWIFT/JET-X**



**XMM-Newton**



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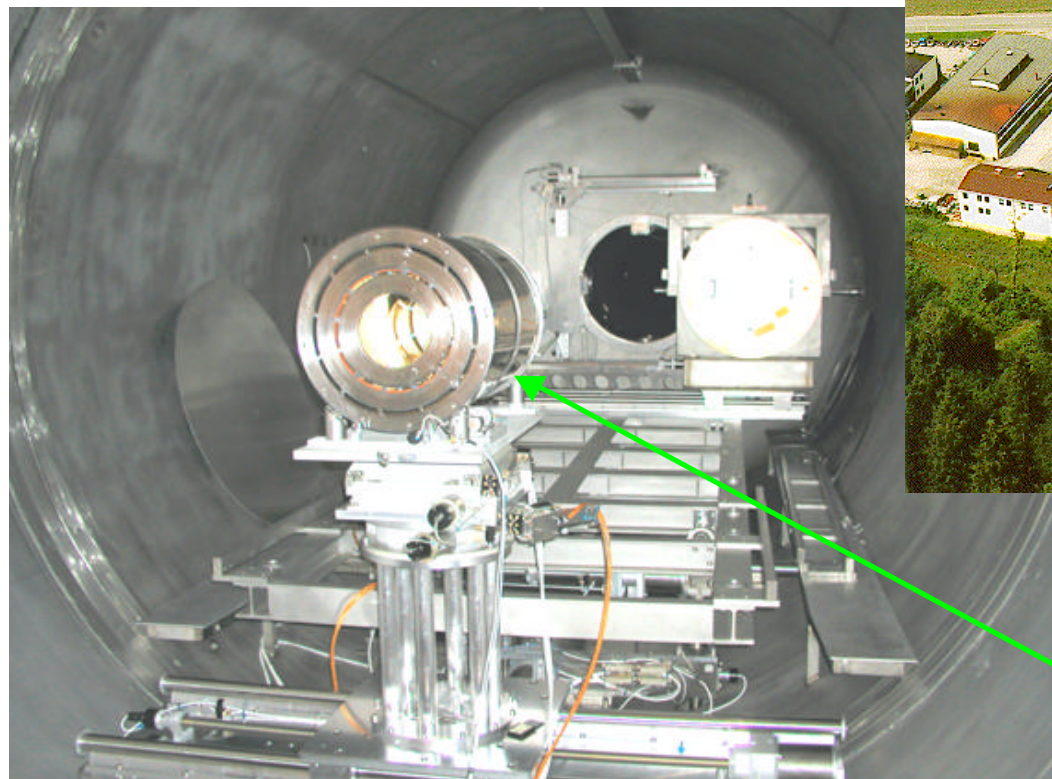
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# *Full-illumination X-ray tests at the Panter-MPE facility (July '02)*



**Electroformed Wolter 1 Shell**

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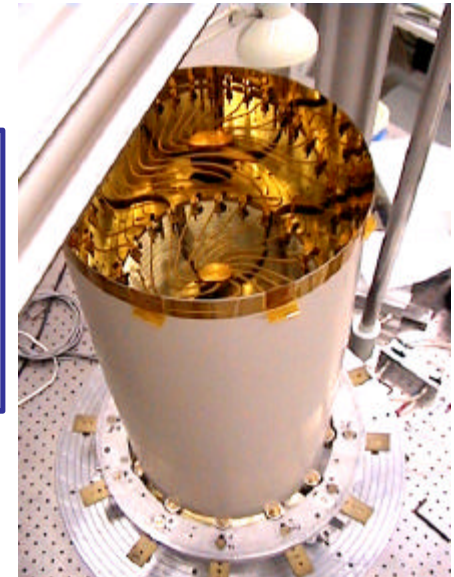
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# *X-ray imaging test of thin shell from JET-X mandrel (July '02)*

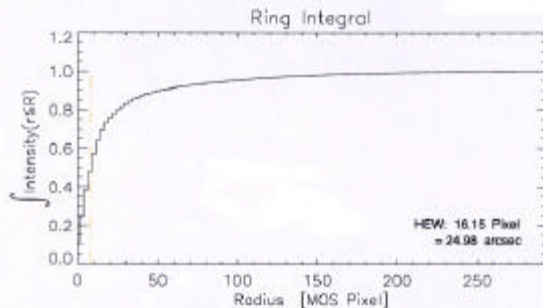
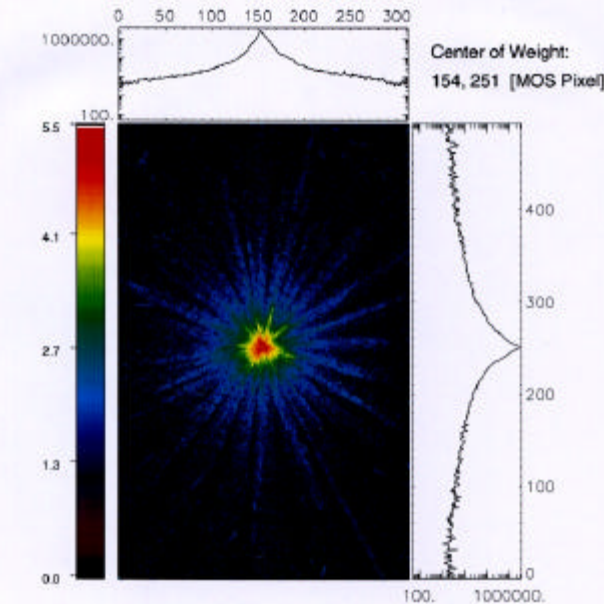
## *@ Panter-MPE*

### *1.5 keV, Gold Coating*

- Diam. = 30 cm
- Wall thickness = 130 mic
- 0.29 XMM shell
- 0.12 SWIFT shell,



**HEW<sub>meas</sub> = 25 arcsec**



JET-X MOS@PANTER/MPE

JXA1K.fits

superthin mirror shell @ 1.5 keV

gh@PANTER/MPE Thu Jul 18 16:42:22 2002

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# Mass

Est. mass of electroformed replica telescope for the Con-X HXT is:  
53 kg/unit or 159 kg/SC. **This fits within mass allowance.**

Shell/diameter thickness ratio is **0.12 SWIFT/JET-X, 0.29 XMM**

Mean HXT substrate thickness is 110 microns, Ni density is 8.9  
Thickness x density = 979

Mean SXT substrate thickness is 440 microns, Glass density is 2.5  
Thickness x density = 1100

**Electroformed HXT substrates are less dense than SXT's**



## **Inner Shells are Coated with Iridium, Outer Shells with W/Si Multilayer**

- **Larger effective area at 40 keV**
- **Lower cost,  
mandrels for Ir shells do not have to be polished as thoroughly  
as the mandrels for the W/Si shells**
- **Faster production  
Depositing single layer Ir requires less time  
and effort than depositing W/Si ML**



## 40 keV Reflectivity Vs. Angle for Several Coatings

Ni/C

W/Si

Ir95%

Au95%

1.0

0.8

0.6

0.4

0.2

0

0

0.06

0.12

0.18

0.24

0.3

Angle (deg)

0

4

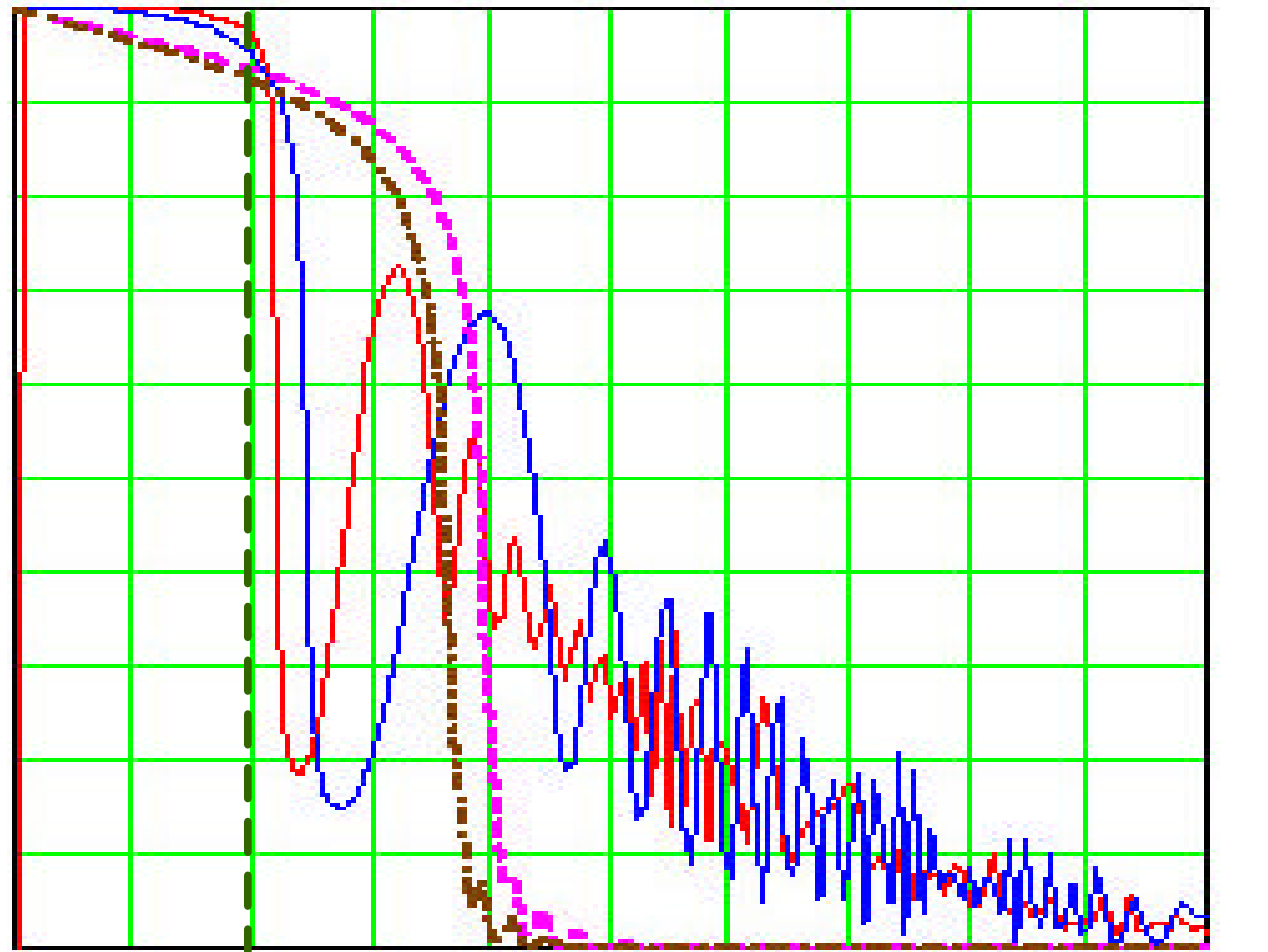
8

12

16

20

Radius (cm)



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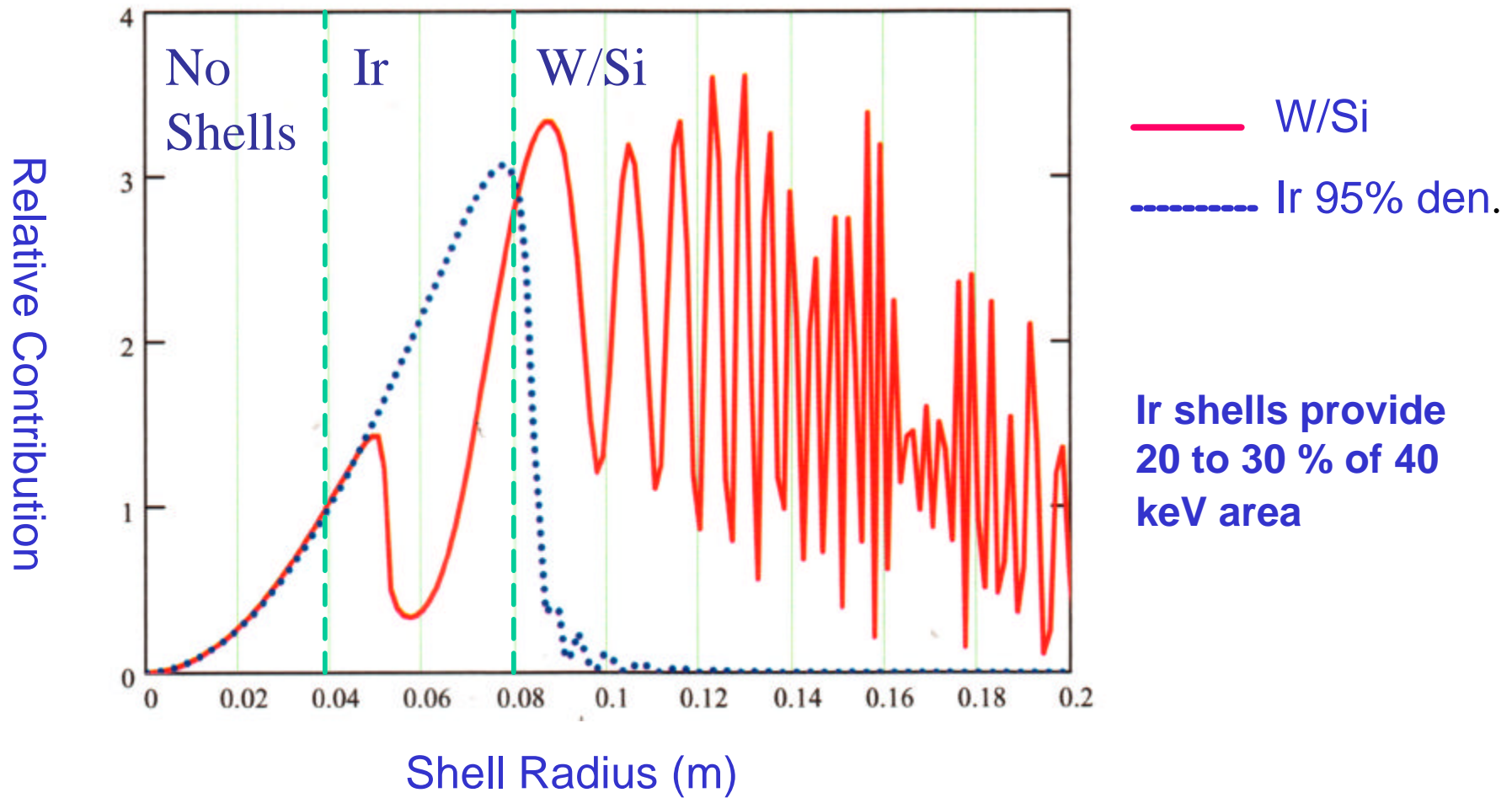
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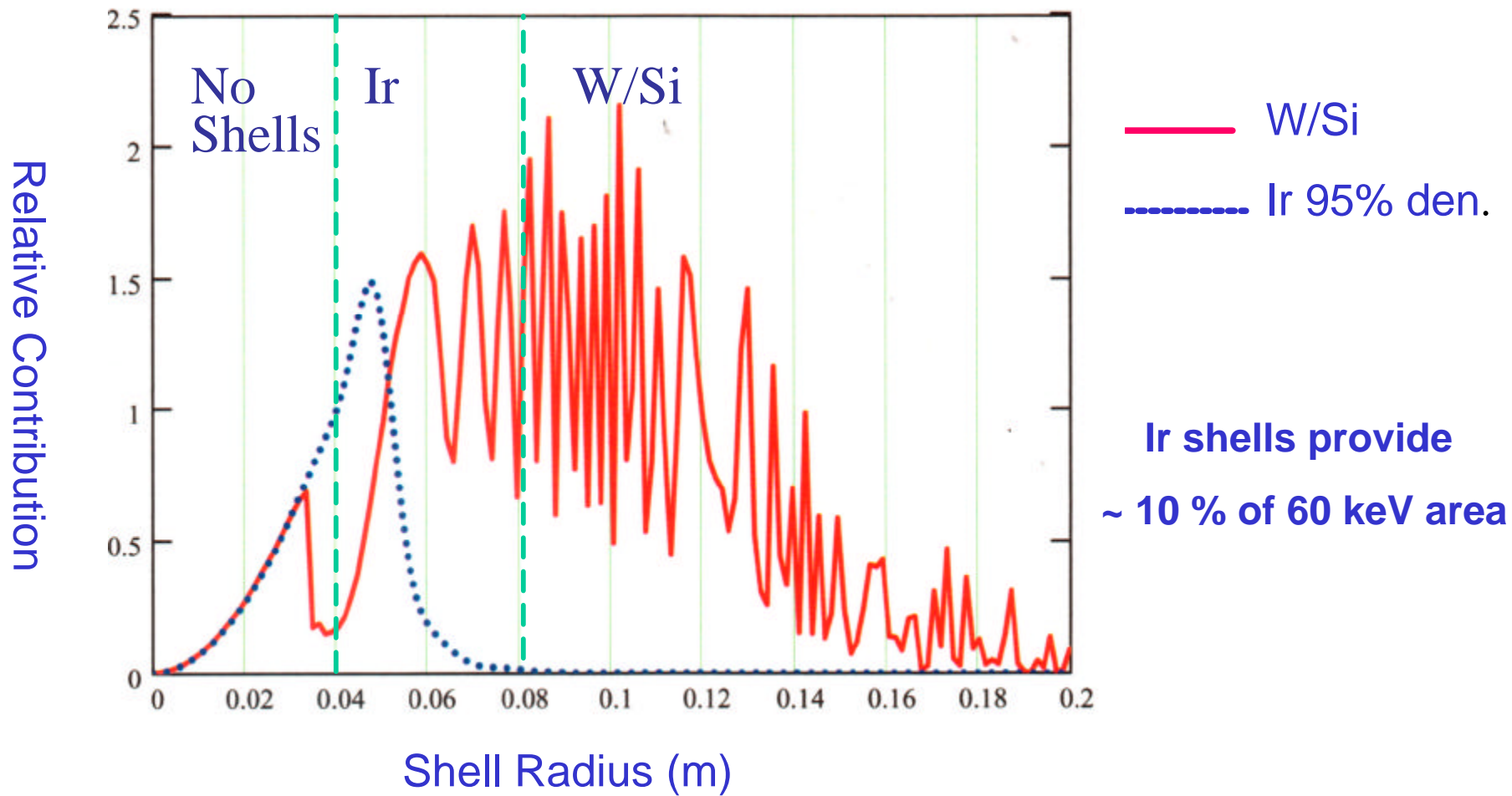
# Relative Contribution to 40 keV Effective Area as a Function of Shell Radius

## Change coating from Ir to W/Si at 8 cm radius



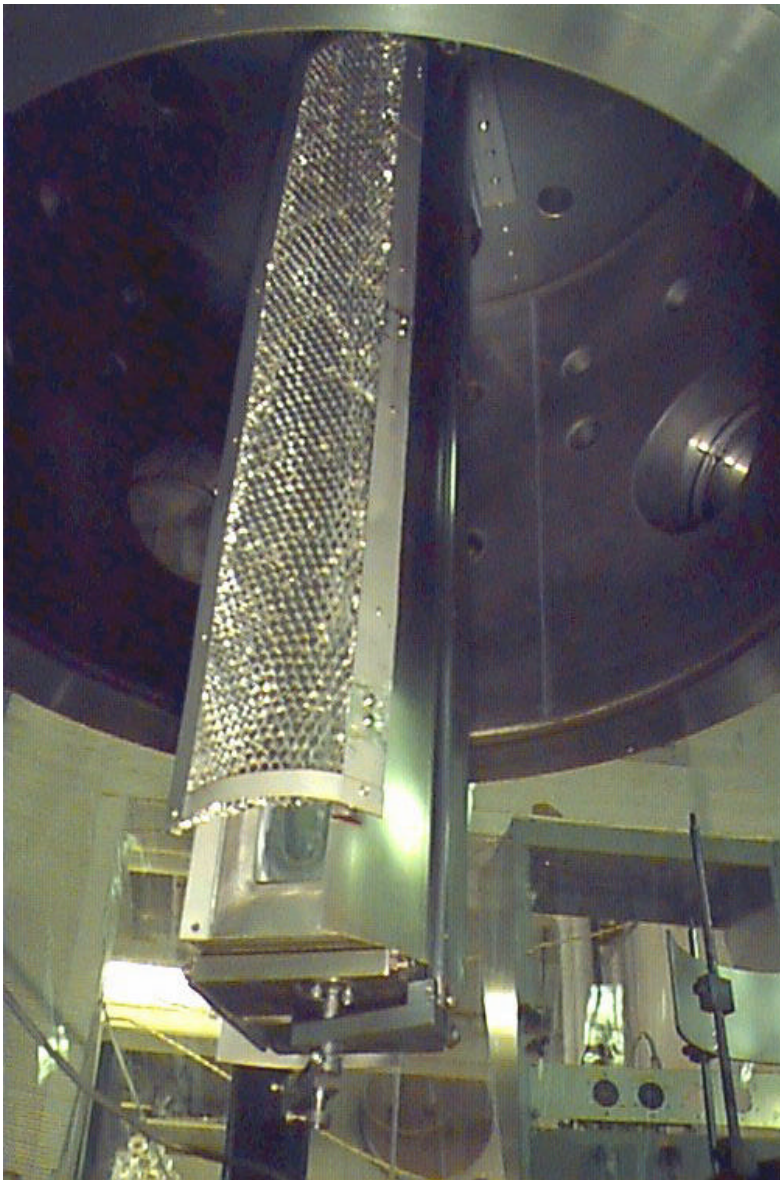
# Relative Contribution to 60 keV Effective Area as a Function of Shell Radius

## Change coating from Ir to W/Si at 8 cm radius



Result of Coating Inner Shells with Ir and Outer Shells with W/Si  
Per Cent Change in Effective Area With Respect to All with W/Si

Shell Range <b>Outermost - Innermost</b> <u>0 - 100 Coating</u>	<u>40 keV</u>	<u>60 keV</u>
1 - 55 W/Si 56 - 112 Ir	+ 30 %	- 26.7 %
1 - 83 W/Si 84 - 112 Ir	+ 11.5 %	0 %



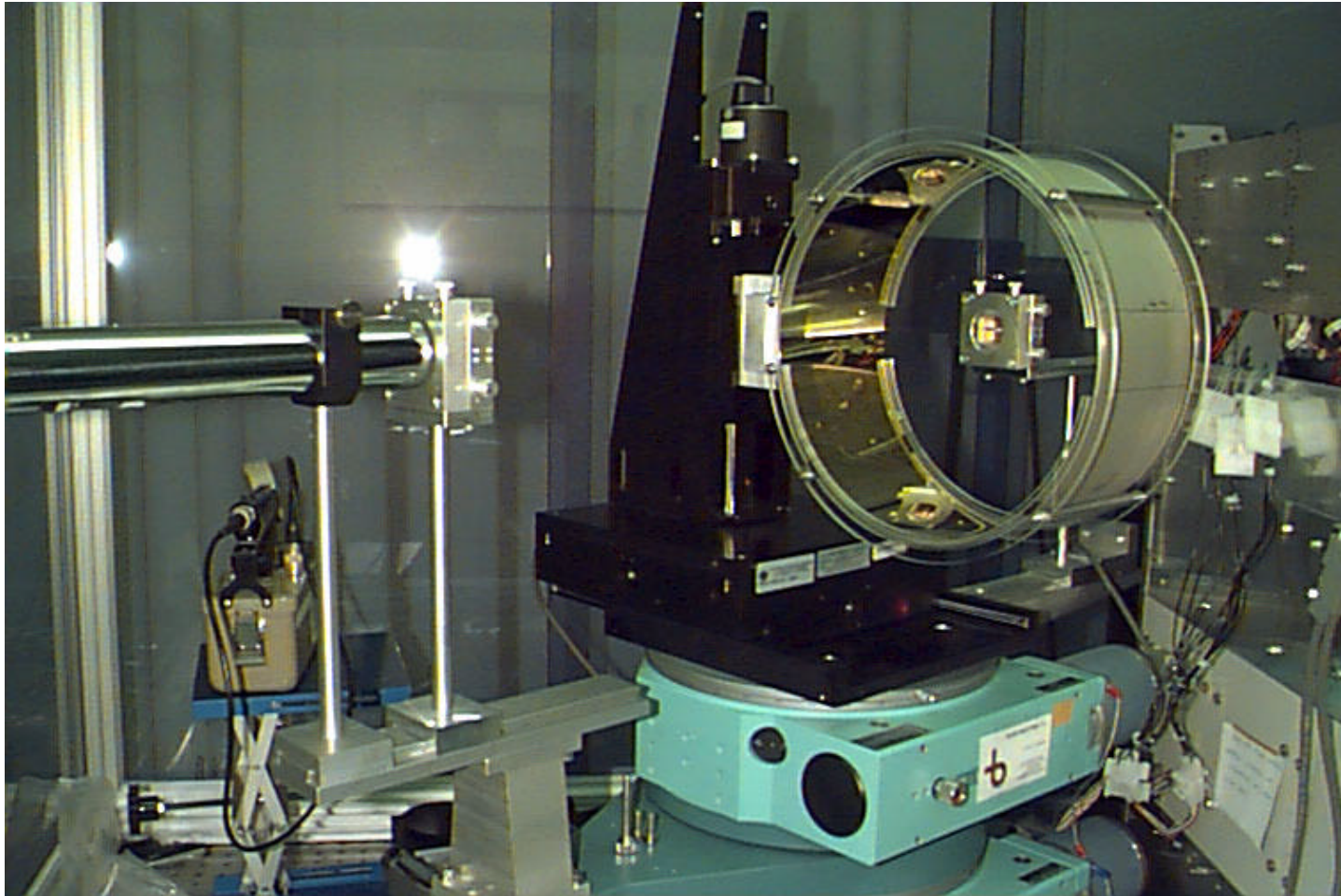
Jensen and Christensen, 2002 reported that the roughness of a multilayer coating can be reduced by installing a collimator between the source and the target substrate

Introducing collimator in SAO chamber reduced WSi interface roughness.

**4.5  $\longrightarrow$  3.5 Å rms  
on Si Wafer**



## Small Length Shell with W/Si on Only ~ 45 deg. of Azimuth



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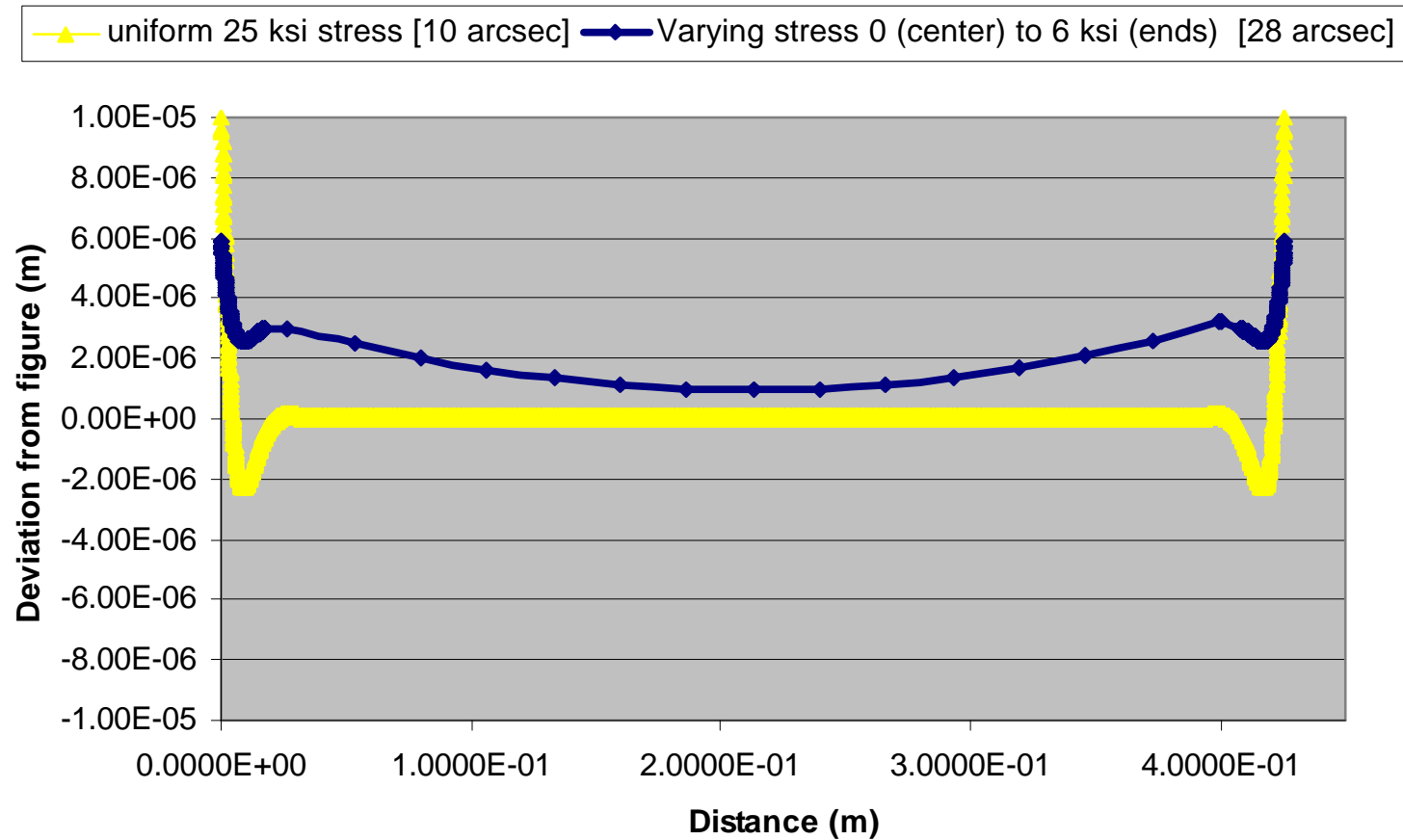
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# Stress in Multilayer Coatings

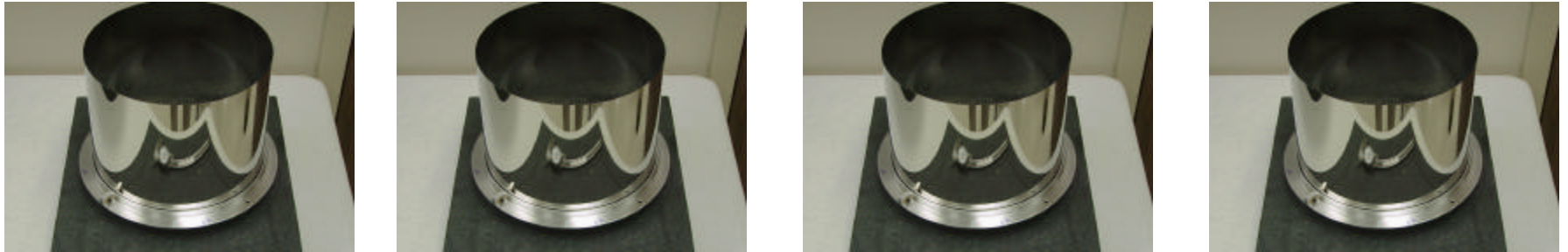
- Coating shell only portion of azimuth (to allow multiple depositions on single shell) resulted in distortion
- Measured stress for 30 layers, 4 nm period, W/Si on Si wafer is few 100 Pa
- Stress is partially intrinsic and partially a result of mismatch in coefficients of thermal expansion between Ni shell and W/Si coating
- Not clear if this is a problem for uniformly coated shells with uniform stress; where we expect only end effects
- Modelling by MSFC indicates that if there are no axial temperature gradients during coating the effect upon the resolution is small

## MSFC Model of Effect of Stress in Coating Upon Resolution

Figure deviations in HXT prototype shell



# MSFC Shells for Stress Tests on Fully Coated Shells



- MSFC has fabricated 4 shells (not smooth mandrel)
- Initial measurements of figure, this week (May 5)
- Delivery to SAO for coating. week of May 12
- Return to MSFC for figure check, week of May 26

# Measures to Relieve Stress

If stress is a problem for uniformly coated shells

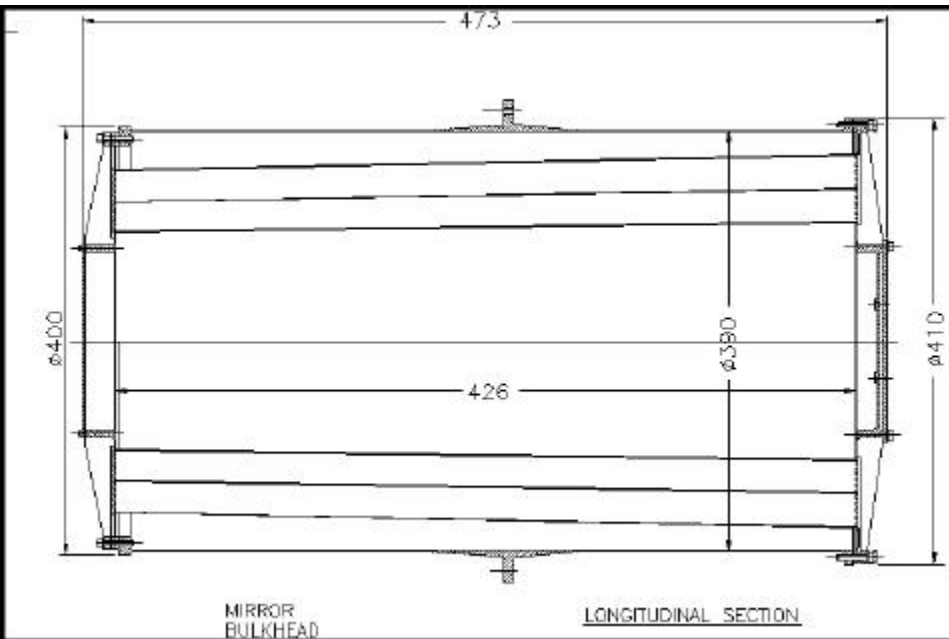
- Adjust pressure during coating process
- Anneal shells
- If the above fail: coat the outside of the shells with single layer of W to balance stress from interior layer



# SAO/OAB/MSFC Integral Shell Prototype For X-ray Testing

**Focal Length = 10000 mm**

**Mirror length = 426 mm**



✓ 3 shells ( $\lambda = 250, 270, 280$  mm) provided by OAB;

✓ deposition of the multilayer films at CfA;

✓ 2 additional shells ( $\lambda = 240$  and  $150$  mm) provided by MSFC. The  $150$  mm shell will be coated with single layer, Ir;

✓ integration at OAB;

✓ full-illumination tests at the 102 m Hard X-ray facility of NASA/MSFC.

**X-ray tests to be re-scheduled from: Summer 2003**

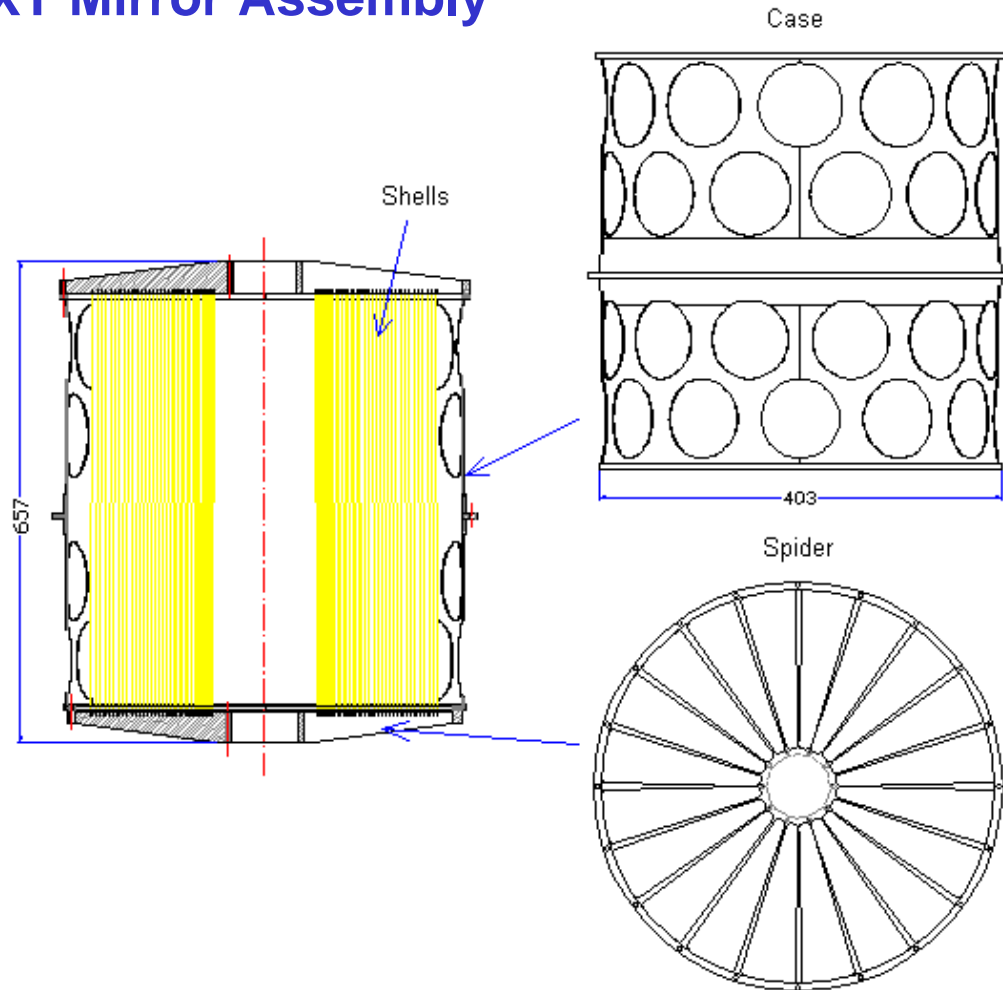
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# Prototype HXT Mirror Assembly



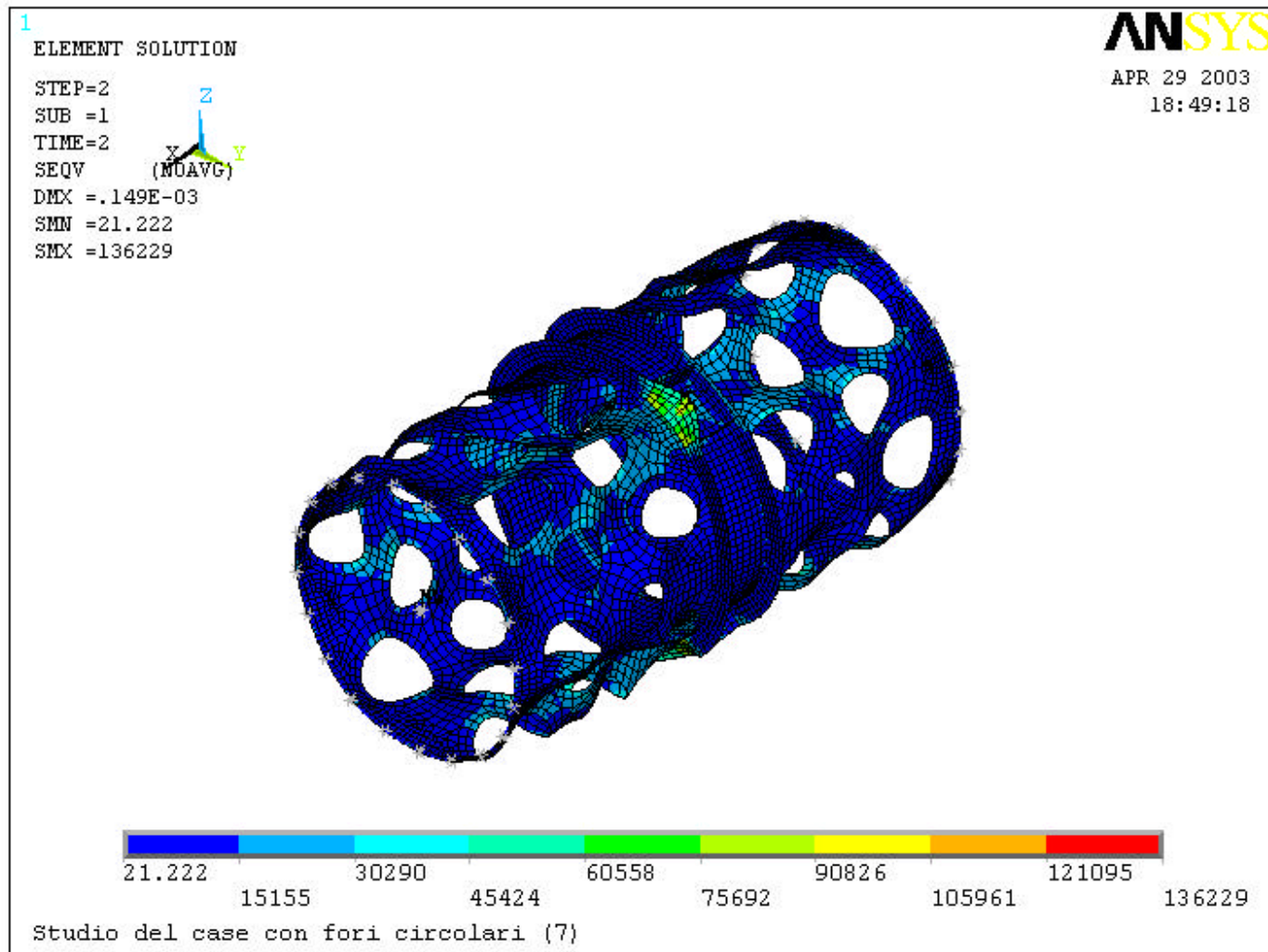
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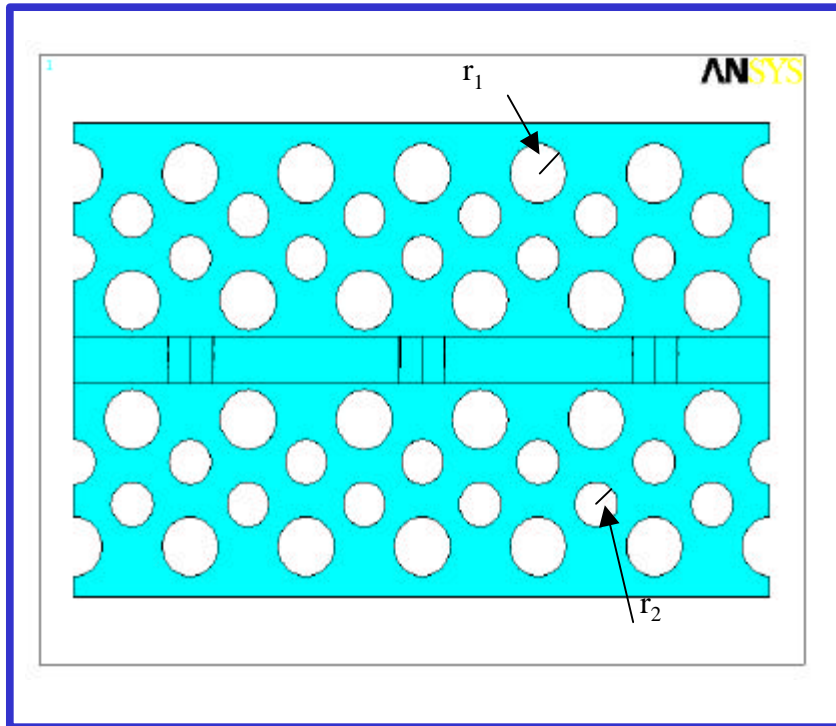
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# OAB Structural Analysis of Support Case

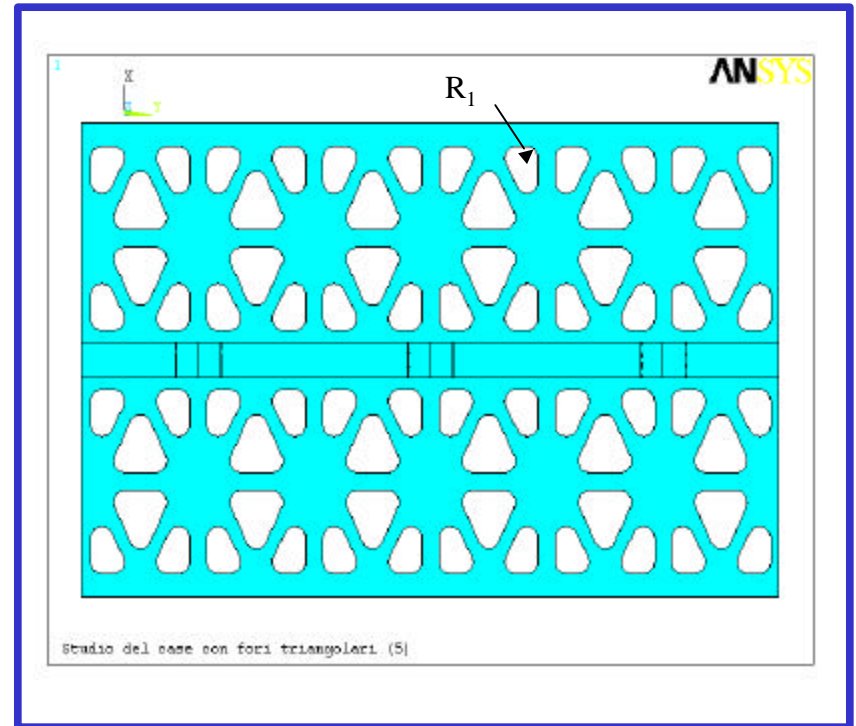


# OAB Structural Analysis of Support Case

## Round Holes



## Triangular Holes



## OAB Structural Analysis of Support Case

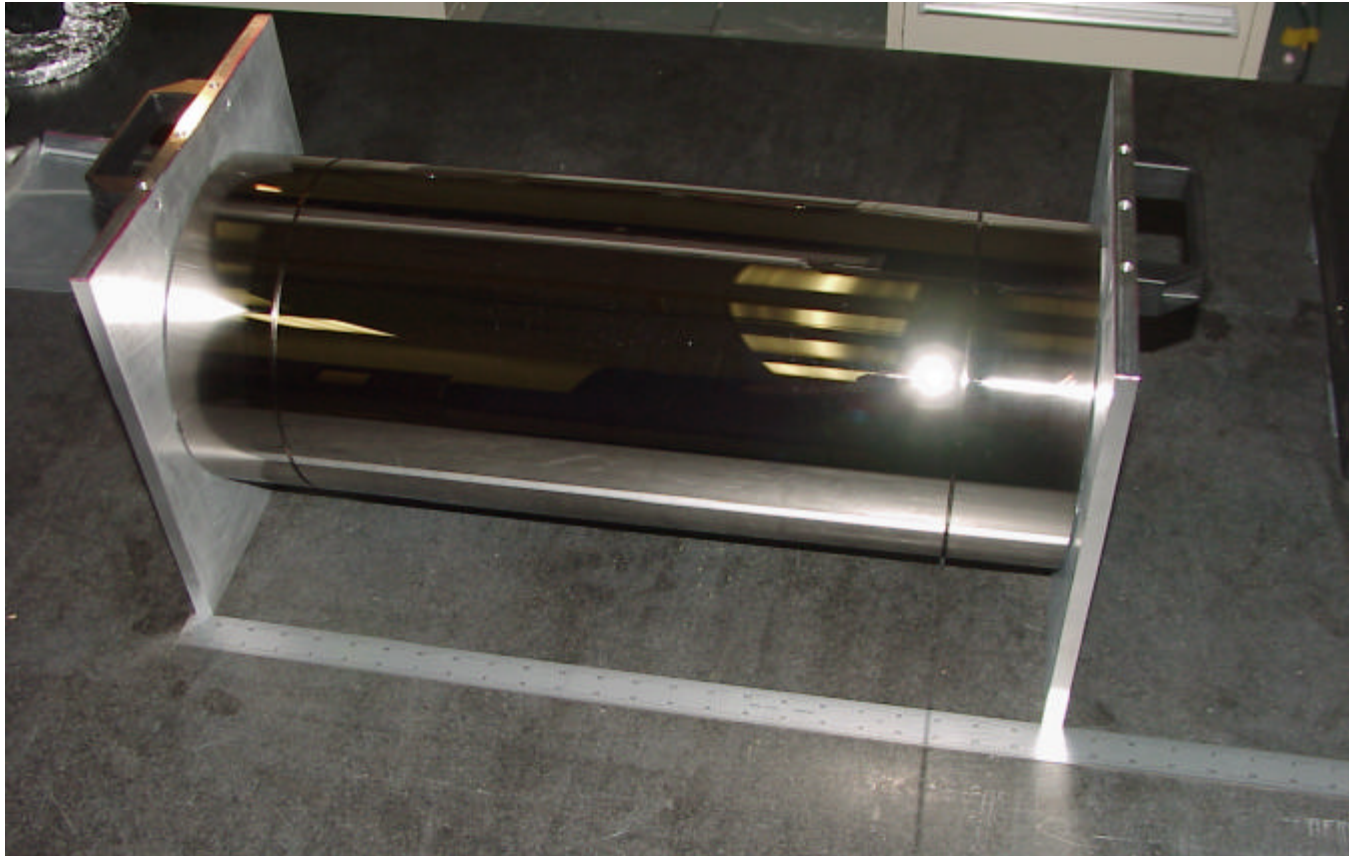
Name		Circular 6	Circular 7	Triangular 5
Image		Fig. 1	Fig. 1	Fig. 2
Case thickness	[mm]	1.1	1.1	1.2
R1	[cm]	5.0	5.0	2.0
R2	[cm]	3.75	3.75	---
Ribs at the edge of holes		Yes	No	No
Total mass (*)	[kg]	54.3	54.4	54.0
Von Mises equivalent stress (20g +x)	[MPa]	205.5	136	234.4
Von Mises equivalent stress (20g +y)	[MPa]	127.4	302	195.9
Von Mises equivalent stress (20g +z)	[MPa]	134.0	320	209.6
Frequency (I mode)	[Hz]	68.2	70.7	63.9
Euler critical factor (20g +x)		14.6	9.14	5.19
Euler critical factor (20g +z)		7.8	4.31	3.25

(\*) case + spiders + mirror shells.

High Resonant Frequency



## MSFC Polished Mandrel For Prototype Mirror



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### 3 Mandrels in Different Stages of Preparation at OAB



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